

N-Ch and P-Channel MOSFET

## **General Description**

The WSP4606 is the highest performance trench N-ch and P-ch MOSFETs with extreme high cell density , which provide excellent RDSON and gate charge for most of the synchronous buck converter applications .

The WSP4606 meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

#### **Features**

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- 100% EAS Guaranteed
- Green Device Available

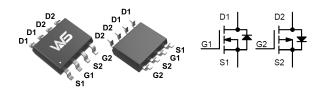
### **Product Summery**

BVDSS	RDSON	ID
30V	18mΩ	7A
-30V	30mΩ	-6A

## **Applications**

- Power management in half bridge and inverters
- DC-DC Converter
- Load Switch

### **SOP-8 Pin Configuration**



## **Absolute Maximum Ratings**

Symbol	Parameter	Rati		
Зушьог	Falanietei	N-Channel	P-Channel	Units
V <sub>DS</sub>	Drain-Source Voltage	30	-30	V
$V_{GS}$	Gate-Source Voltage	±20	±20	V
I <sub>D</sub> @T <sub>C</sub> =25℃	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	7.0	-6	Α
I <sub>D</sub> @T <sub>C</sub> =100℃	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	6	-4	Α
I <sub>DM</sub>	Pulsed Drain Current <sup>2</sup>	20	-12	Α
EAS	Single Pulse Avalanche Energy <sup>3</sup>	72	59	mJ
I <sub>AS</sub>	Avalanche Current	21	-19	Α
P <sub>D</sub> @T <sub>C</sub> =25℃	Total Power Dissipation <sup>4</sup>	2.5	2.08	W
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	-55 to 150	$^{\circ}$
TJ	Operating Junction Temperature Range	-55 to 150	-55 to 150	$^{\circ}$

#### **Thermal Data**

Symbol	Parameter	Тур.	Max.	Unit
R <sub>0JA</sub>	Thermal Resistance Junction-Ambient <sup>1</sup>		85	°C/W
R <sub>eJC</sub>	Thermal Resistance Junction-Case <sup>1</sup>		50	°C/W





# Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS}$ =0V , $I_D$ =250uA	30			V
$\triangle BV_{DSS}/\triangle T_{J}$	BVDSS Temperature Coefficient	Reference to 25°C , I <sub>D</sub> =1mA		0.034		V/°C
В	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =10V , I <sub>D</sub> =6A		18	28	m()
R <sub>DS(ON)</sub>		$V_{GS}$ =4.5V , $I_D$ =5A		25	32	mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage	\/ =\/   =250\	1.0	1.5	2.5	V
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	$V_{GS}=V_{DS}$ , $I_D=250uA$		-5.8		mV/℃
	Drain Source Leakage Current	V <sub>DS</sub> =30V , V <sub>GS</sub> =0V , T <sub>J</sub> =25℃			1	
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =30V , V <sub>GS</sub> =0V , T <sub>J</sub> =55℃			5	- uA
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{\text{GS}} = \pm 20 \text{V}$ , $V_{\text{DS}} = 0 \text{V}$			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =15V , I <sub>D</sub> =5A		10		S
R <sub>g</sub>	Gate Resistance	V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , f=1MHz		2.5		Ω
Qg	Total Gate Charge (4.5V)			7.2		
Q <sub>gs</sub>	Gate-Source Charge	$V_{DS}$ =20V , $V_{GS}$ =4.5V , $I_{D}$ =6A		1.4		nC
$Q_gd$	Gate-Drain Charge			2.2		
T <sub>d(on)</sub>	Turn-On Delay Time			4.1		
T <sub>r</sub>	Rise Time	$V_{DD}$ =12V , $V_{GS}$ =10V , $R_{G}$ =3.3 $\Omega$		9.8		no
$T_{d(off)}$	Turn-Off Delay Time	I <sub>D</sub> =5A		15.5		ns
T <sub>f</sub>	Fall Time			6.0		
C <sub>iss</sub>	Input Capacitance			550		
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> =25V , V <sub>GS</sub> =0V , f=1MHz		68		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			55		

### **Guaranteed Avalanche Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
EAS	Single Pulse Avalanche Energy <sup>5</sup>	V <sub>DD</sub> =25V , L=0.1mH , I <sub>AS</sub> =10A	16			mJ

### **Diode Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current <sup>1,6</sup>	-V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			7	Α
I <sub>SM</sub>	Pulsed Source Current <sup>2,6</sup>				20	Α
$V_{SD}$	Diode Forward Voltage <sup>2</sup>	$V_{GS}$ =0 $V$ , $I_{S}$ =5 $A$ , $T_{J}$ =25 $^{\circ}\mathbb{C}$			1.2	V

#### Note:

- 1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper,t<10sec.
- 2.The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%
- 3. The EAS data shows Max. rating . The test condition is  $V_{DD}$ =25V,  $V_{GS}$ =10V,L=0.1mH,  $I_{AS}$ =10A
- 5.The Min. value is 100% EAS tested guarantee.
- 6. The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.



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# Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =-250uA	-30			V
$\triangle BV_{DSS}/\triangle T_{J}$	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25℃ , I <sub>D</sub> =-1mA		-0.085		V/°C
В	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =-10V , I <sub>D</sub> =-6A		30	45	mΩ
R <sub>DS(ON)</sub>	Static Diam-Source On-Nesistance	V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-3A		48	65	11122
$V_{GS(th)}$	Gate Threshold Voltage		-1.0	-1.5	-2.5	٧
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	VGS-VDS , ID250UA		0.375		mV/℃
	Drain Source Leakage Current	V <sub>DS</sub> =-24V , V <sub>GS</sub> =0V , T <sub>J</sub> =25℃			1	
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =-24V , V <sub>GS</sub> =0V , T <sub>J</sub> =55℃			5	uA
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS}$ = $\pm 20 V$ , $V_{DS}$ = $0 V$			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =-10V , I <sub>D</sub> =-6A		6		S
$Q_g$	Total Gate Charge (-4.5V)			6.4		
$Q_{gs}$	Gate-Source Charge	V <sub>DS</sub> =-20V , V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-6A		2.7		nC
$Q_{gd}$	Gate-Drain Charge			3.1		
T <sub>d(on)</sub>	Turn-On Delay Time			9		
T <sub>r</sub>	Rise Time	$V_{DD}$ =-12V , $V_{GS}$ =-10V , $R_{G}$ =3.3 $\Omega$ ,		16.6		
$T_{d(off)}$	Turn-Off Delay Time	I <sub>D</sub> =-5A		21		ns
T <sub>f</sub>	Fall Time			21.6		
C <sub>iss</sub>	Input Capacitance			645		
Coss	Output Capacitance	V <sub>DS</sub> =-25V , V <sub>GS</sub> =0V , f=1MHz		272		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			105		

### **Guaranteed Avalanche Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
EAS	Single Pulse Avalanche Energy <sup>5</sup>	V <sub>DD</sub> =-25V , L=0.1mH , I <sub>AS</sub> =-10A	16			mJ

#### **Diode Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current <sup>1,6</sup>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			-6	Α
I <sub>SM</sub>	Pulsed Source Current <sup>2,6</sup>				-12	Α
$V_{SD}$	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =-6A , T <sub>J</sub> =25℃			-1.2	V

#### Note:

- 1.The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper,t<10sec.
- 2.The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%
- 3. The EAS data shows Max. rating . The test condition is  $V_{DD}$ =-25V, $V_{GS}$ =-10V,L=0.1mH, $I_{AS}$ =-10A
- 4.The power dissipation is limited by 150 ℃ junction temperature
- 5. The Min. value is 100% EAS tested guarantee.
- 6. The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.





# **N-Channel Typical Characteristics**

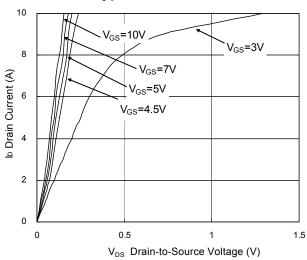


Fig.1 Typical Output Characteristics

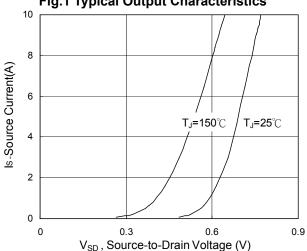
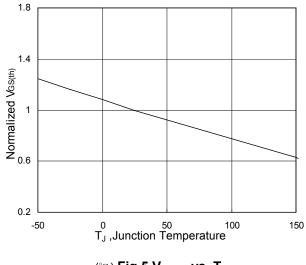


Fig.3 Forward Characteristics of Reverse



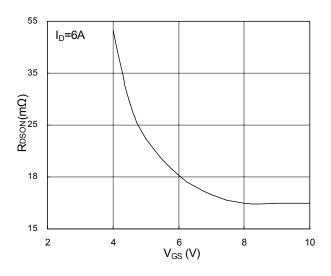


Fig.2 On-Resistance vs. G-S Voltage

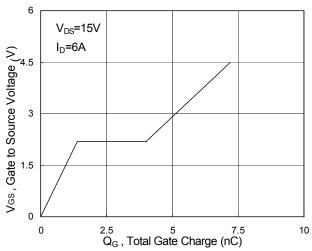


Fig.4 Gate-charge Characteristics

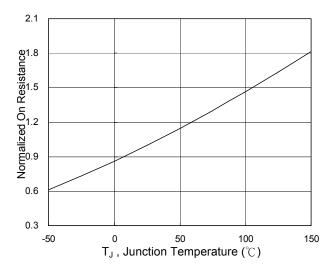
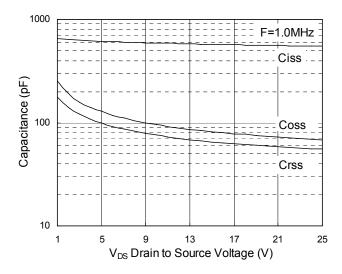


Fig.6 Normalized R<sub>DSON</sub> vs. T<sub>J</sub>





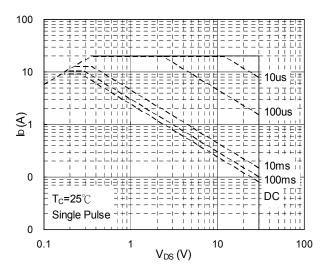


Fig.7 Capacitance

Fig.8 Safe Operating Area

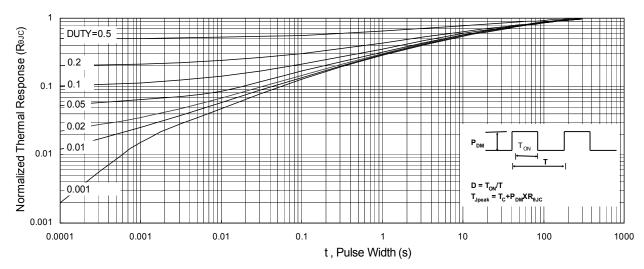


Fig.9 Normalized Maximum Transient Thermal Impedance

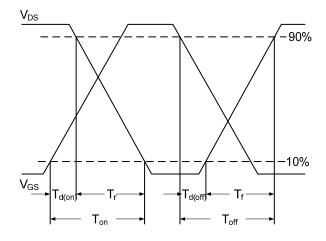


Fig.10 Switching Time Waveform

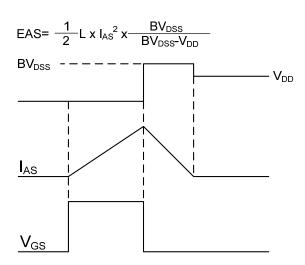


Fig.11 Unclamped Inductive Waveform





# P-Channel Typical Characteristics

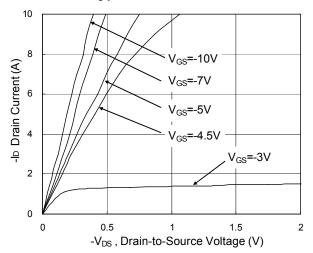


Fig.1 Typical Output Characteristics

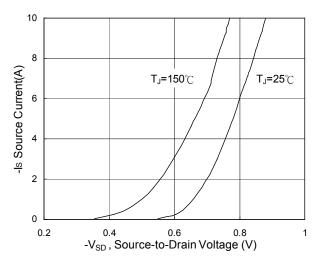


Fig.3 Forward Characteristics of Reverse

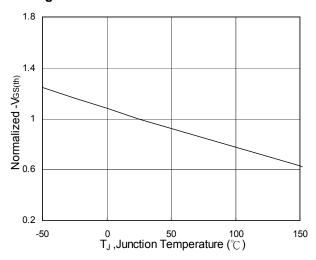


Fig.5 Normalized  $V_{GS(th)}$  vs.  $T_J$ 

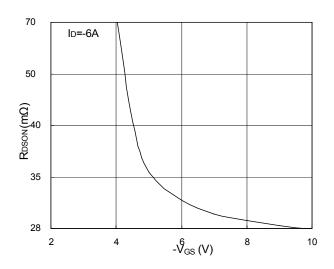
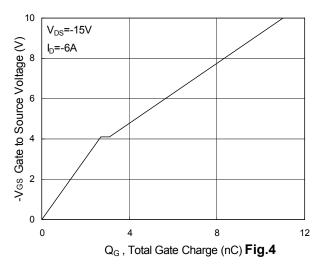
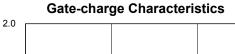


Fig.2 On-Resistance vs. Gate-Source





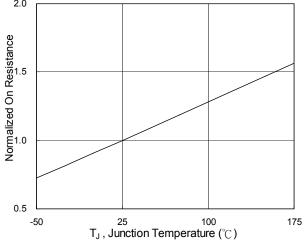
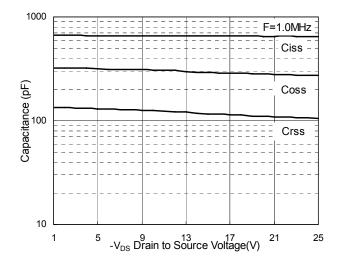


Fig.6 Normalized R<sub>DSON</sub> vs. T<sub>J</sub>







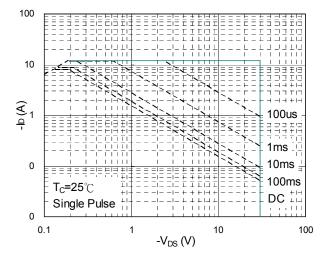


Fig.7 Capacitance

Fig.8 Safe Operating Area

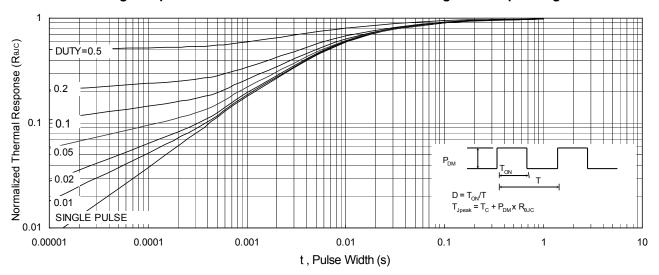
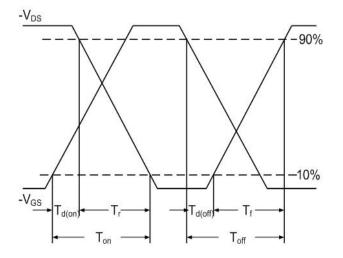


Fig.9 Normalized Maximum Transient Thermal Impedance





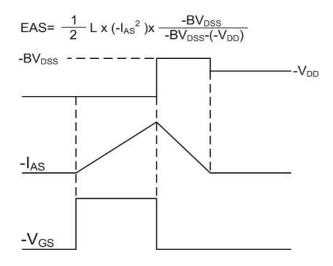


Fig.11 Unclamped Inductive Waveform



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